

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Re:    Application of:        Volker ALBRECHT, et al.  
      Serial No.:            To Be Assigned  
      Filed:                Herewith as national phase of International Patent  
                                 Application PCT/EP2004/007359, filed 6 July 2004  
For:                        **METHOD AND DEVICE FOR PREDICTING A  
                                 FAILURE FREQUENCY**

Mail Stop: PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

January 10, 2006

**INFORMATION DISCLOSURE STATEMENT**

S i r:

In accordance with the provisions of 37 C.F.R. § 1.97, Applicants hereby make of record the documents listed on the accompanying PTO-1449 Form (1 page) for consideration by the Examiner in connection with the examination of the above-identified patent application. While the references are being submitted herewith, some or all of the references may not constitute prior art under the U.S. patent laws.

This Information Disclosure Statement is filed under 37 C.F.R. §1.97 (b), before the mailing date of a First Office Action. Therefore, no fee is believed due.

In the event any additional fee is due in connection with this response or if any fee has been overpaid, the deficiency or overpayment should be charged to our Deposit Account No. 50-0552.

10/904257

710.1035

AP20 Rec'd PCT/TO 10 JAN 2006

It is respectfully requested that the references cited in the accompanying PTO-1449 form be considered and made of record. It is respectfully submitted that the pending claims are patentable over all of the references made of record at this time.

Respectfully submitted,

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FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 710.1035	10/564257 APPLICATION NO. To be assigned
LIST OF PRIOR ART CITED BY APPLICANT  (Use several sheets if necessary)		APPLICANT Volker ALBRECHT, et al.	
		FILING DATE Herewith	GROUP To be assigned

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	A01	US 2001/0023376	Sep. 20, 2001	Uchida et al.	700	101	
	A02						
	A03						
	A04						
	A05						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
	A06	EP 1 146 468	Oct. 17, 2001	EP – Europe			In English	
	A07	JP 10-107793	Apr. 24, 1998	JP – Japan			JPO computer translation, See specification	
	A08	WO 00/72212	Nov. 30, 2000	WO – WIPO			In English	
	A09	DE 198 48 094	Apr. 20, 2000	DE – Germany			See specification	
	A10	EP 1 160 712	Dec. 5, 2001	EP – Europe			In English	
	A11	WO 01/26005	Apr. 12, 2001	WO – WIPO			In English	
	A12	DE 197 51 273	May 27, 1999	DE – Germany			See specification, English abstract	

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	A13	R. Bothwell et al., Reliability evaluation: A field experience from Motorola's cellular base transceiver system, Reliability and Maintainability Symposium, 1996 Proceedings. International Symposium on Product Quality and Integrity., Annual Las Vegas, NV, USA, 22-25 Jan. 1996, IEEE, US, 22 January 1996, pages 348 to 359, XP010160856, ISBN 0-7803-3112-5
	A14	E.K. Melnick et al., R&M Design Influence from Spreadsheet Analysis, 1988 Proceedings Annual Reliability and Maintainability, 26 January 1988, pages 336 to 339, XP010072459
	A15	P. Wirkstrom et al., Reliability, availability and maintainability (RAM) of high power variable speed drive systems (VSDS), Petroleum and Chemical Industry Conference, 1998, Industry Applications Society 45 <sup>th</sup> Annual Indianapolis, IN, USA, 28 - 30 September 1998, New York, NY, USA, IEEE, US, 28 September 1998, pages 139 to 148, XP010312472, ISBN 0-7803-4897-4
	A16	T. Elmore, Case study: modular ate system design, Conference Proceedings Article, 18 September 2000, pages 576 – 583, XP010522042

EXAMINER	DATE CONSIDERED
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.